May 2009



## **FDMS6681Z**

# P-Channel PowerTrench® MOSFET

-30 V, -49 A, 3.2 m $\Omega$ 

#### **Features**

- Max  $r_{DS(on)}$  = 3.2 m $\Omega$  at  $V_{GS}$  = -10 V,  $I_D$  = -21.1 A
- Max  $r_{DS(on)}$  = 5.0 m $\Omega$  at  $V_{GS}$  = -4.5 V,  $I_D$  = -15.7 A
- Advanced Package and Silicon combination for low r<sub>DS(on)</sub>
- HBM ESD protection level of 8kV typical(note 3)
- MSL1 robust package design
- RoHS Compliant

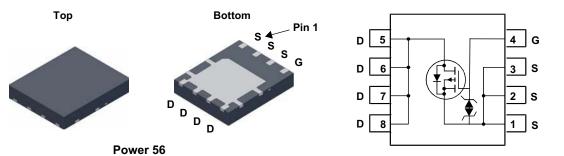


## **General Description**

The FDMS6681Z has been designed to minimize losses in load switch applications. Advancements in both silicon and package technologies have been combined to offer the lowest  $r_{DS(on)}$  and ESD protection.

## **Applications**

- Load Switch in Notebook and Server
- Notebook Battery Pack Power Management



# MOSFET Maximum Ratings TA = 25 °C unless otherwise noted

Symbol	Parameter			Ratings	Units
V <sub>DS</sub>	Drain to Source Voltage			-30	V
$V_{GS}$	Gate to Source Voltage			±25	V
	Drain Current -Continuous (Package limited)	T <sub>C</sub> = 25 °C		-49	
	-Continuous (Silicon limited)	T <sub>C</sub> = 25 °C		-116	T ,
'D	-Continuous	T <sub>A</sub> = 25 °C	(Note 1a)	-21.1	A
	-Pulsed			-90	
Б	Power Dissipation	T <sub>C</sub> = 25 °C		73	w
$P_{D}$	Power Dissipation	T <sub>A</sub> = 25 °C	(Note 1a)	2.5	
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Junction Temperature Range			-55 to +150	°C

#### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance, Junction to Case	1.7	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	50	C/VV

#### **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS6681Z	FDMS6681Z	Power 56	13 "	12 mm	3000 units

# **Electrical Characteristics** $T_J = 25 \, ^{\circ}\text{C}$ unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	I <sub>D</sub> = -250 μA, V <sub>GS</sub> = 0 V	-30			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = -250 μA, referenced to 25 °C		20		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = -24 V, V <sub>GS</sub> = 0 V			-1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	V <sub>GS</sub> = ±25 V, V <sub>DS</sub> = 0 V			±10	μΑ

#### **On Characteristics**

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_{D} = -250 \mu A$	-1	-1.7	-3	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D$ = -250 $\mu$ A, referenced to 25 °C		-7		mV/°C
		V <sub>GS</sub> = -10 V, I <sub>D</sub> = -22.1 A		2.7	3.2	
r <sub>DS(on)</sub>	r <sub>DS(on)</sub> Static Drain to Source On Resistance	$V_{GS} = -4.5 \text{ V}, I_D = -15.7 \text{ A}$		4.0	5.0	mΩ
	$V_{GS} = -10 \text{ V}, I_D = -22.1 \text{ A}, T_J = 125 ^{\circ}\text{C}$		3.9	5.0		
9 <sub>FS</sub>	Forward Transconductance	V <sub>DD</sub> = -10 V, I <sub>D</sub> = -22.1 A		143		S

## **Dynamic Characteristics**

C <sub>iss</sub>	Input Capacitance	V - 45 V V - 0 V		7803	10380	pF
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> = -15 V, V <sub>GS</sub> = 0 V, f = 1 MHz		1540	2050	pF
C <sub>rss</sub>	Reverse Transfer Capacitance	1 - 1 101112		1345	2020	pF

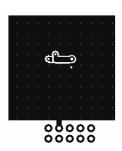
## **Switching Characteristics**

t <sub>d(on)</sub>	Turn-On Delay Time				15	24	ns
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = -15 V, I <sub>D</sub> = -2	$V_{DD}$ = -15 V, $I_{D}$ = -22.1 A, $V_{GS}$ = -10 V, $R_{GEN}$ = 6 $\Omega$		38	61	ns
t <sub>d(off)</sub>	Turn-Off Delay Time	V <sub>GS</sub> = -10 V, R <sub>GEN</sub>			260	416	ns
t <sub>f</sub>	Fall Time				197	316	ns
Qg	Total Gate Charge	V <sub>GS</sub> = 0 V to -10 V			172	241	nC
Qg	Total Gate Charge	V <sub>GS</sub> = 0 V to -5 V	V <sub>DD</sub> = -15 V,		97	136	nC
Q <sub>gs</sub>	Gate to Source Charge		I <sub>D</sub> = -22.1 A		22		nC
Q <sub>ad</sub>	Gate to Drain "Miller" Charge				46		nC

## **Drain-Source Diode Characteristics**

V Sou	Vas Source to Firsin Filinge Forward Voltage F	V <sub>GS</sub> = 0 V, I <sub>S</sub> = -2.1 A (Note 2)		0.68	1.2	V
V <sub>SD</sub>		V <sub>GS</sub> = 0 V, I <sub>S</sub> = -22.1 A (Note 2)		0.79	1.25	V
t <sub>rr</sub>	Reverse Recovery Time	L = 22.1 A di/dt = 100 A/vo		44	71	ns
Q <sub>rr</sub>	Reverse Recovery Charge	I <sub>F</sub> = -22.1 A, di/dt = 100 A/μs		39	63	nC

<sup>1.</sup> R<sub>0JA</sub> is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R<sub>0JC</sub> is guaranteed by design while R<sub>0CA</sub> is determined by the user's board design.



a. 50 °C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



b. 125 °C/W when mounted on a minimum pad of 2 oz copper.

- Pulse Test: Pulse Width < 300 μs, Duty cycle < 2.0%.</li>
   The diode connected between the gate and source servers only as protection against ESD. No gate overvoltage rating is implied.

## Typical Characteristics T<sub>J</sub> = 25 °C unless otherwise noted

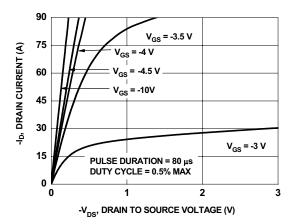


Figure 1. On Region Characteristics

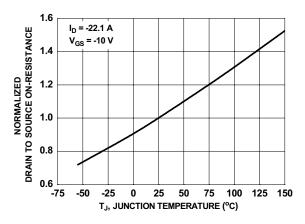


Figure 3. Normalized On Resistance vs Junction Temperature

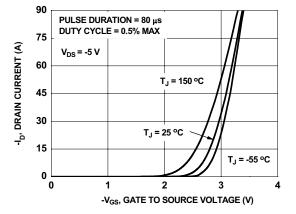


Figure 5. Transfer Characteristics

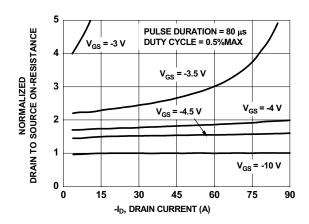


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

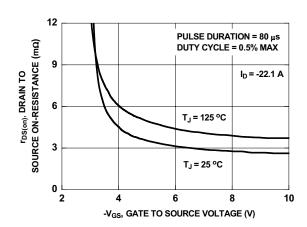


Figure 4. On-Resistance vs Gate to Source Voltage

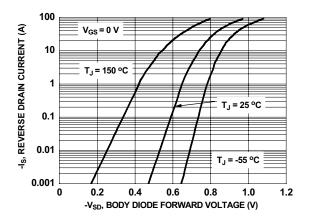


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

# **Typical Characteristics** $T_J = 25$ °C unless otherwise noted

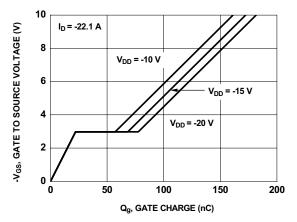


Figure 7. Gate Charge Characteristics

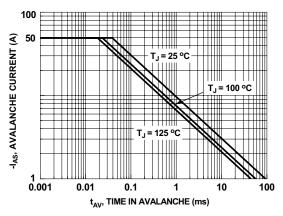


Figure 9. Unclamped Inductive Switching Capability

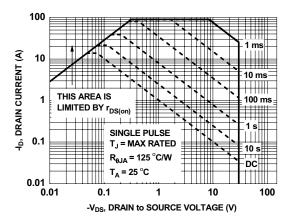


Figure 11. Forward Bias Safe Operating Area

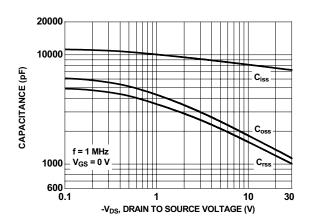


Figure 8. Capacitance vs Drain to Source Voltage

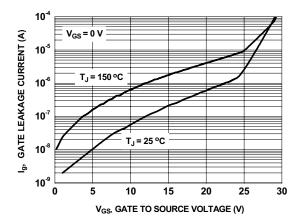


Figure 10.  $I_{gss}$  vs  $V_{gss}$ 

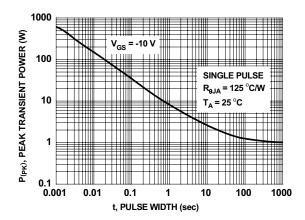


Figure 12. Single Pulse Maximum Power Dissipation

## **Typical Characteristics** T<sub>J</sub> = 25 °C unless otherwise noted

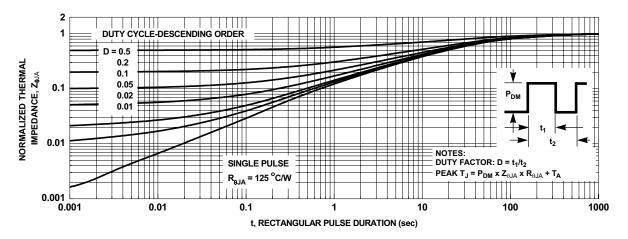
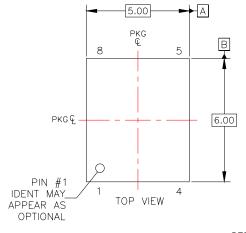
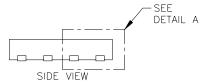
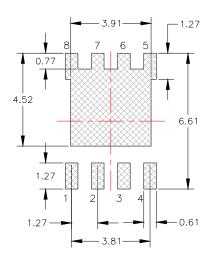


Figure 13. Junction-to-Ambient Transient Thermal Response Curve

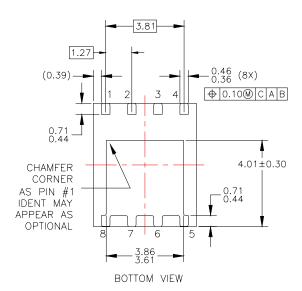
## **Dimensional Outline and Pad Layout**

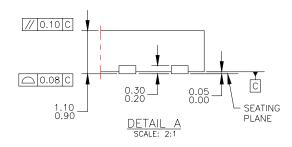


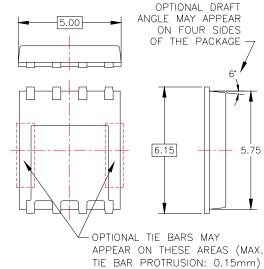




LAND PATTERN RECOMMENDATION







NOTES: UNLESS OTHERWISE SPECIFIED

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  DIMENSIONS DO NOT INCLUDE BURRS
  OR MOLD FLASH. MOLD FLASH OR
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